## In the Claims:

This listing of claims will replace all prior versions, and listings of claims in the application.

1. (Currently Amended) An electrode structure on a p-type III group nitride semiconductor layer, comprising first, second and third electrode layers successively stacked on said semiconductor layer,

said first electrode layer including comprising at least one selected from a first metal group consisting of Hf, Zr, Nb, Ta and Sc,

said second electrode layer <u>comprising</u> -including at least one selected from a second metal group consisting of Ni, Pd and Co, and

said third electrode layer including Au.



- 2. (Original) The electrode structure according to claim 1, wherein said first electrode layer has a thickness in a range from 1 to 500 nm.
- 3. (Original) The electrode structure according to claim 1, wherein said second electrode layer has a thickness of 5 nm or more.
  - 4. (Cancelled)
- 5. (Currently Amended) The electrode structure according to claim 1, wherein said first electrode layer includes comprising comprises a nitride of a metal included in said first metal group, and also includes comprises a compound of Ga and Co a metal included in said second metal group.
  - 6. (Cancelled)

## 7. (Cancelled)

8. (Currently Amended) An electrode structure on a p-type III group nitride semiconductor layer, comprising first, second and third electrode layers successively stacked on said semiconductor layer,

said first electrode layer including comprising at least one selected from a first metal group consisting of Ti, Hf, Zr, Nb, Ta and Sc,

said second electrode layer comprising Ni, and said third electrode layer including comprising Au.

- 9. (Original) The electrode structure according to claim 8, wherein said first electrode layer has a thickness in a range from 1 to 500 nm.
- 10. (Original) The electrode structure according to claim 8, wherein said second electrode layer has a thickness of 5 nm or more.

## 11. (Cancelled)

12. (Currently Amended) The electrode structure according to claim 8, wherein said first electrode layer includes comprises a nitride of a metal included in said first metal group, and also includes comprises a compound of Ga and Ni a metal included in said second metal group.

## 13 - 18 (Cancelled)

semiconductor layer, comprising first, second and third electrode layers successively stacked on said semiconductor layer,
said first electrode layer comprising at least one selected from a first metal group consisting of Hf, Zr, Nb, Ta and Sc,

An electrode structure on a p-type III group nitride

said second electrode layer comprising Ni, and said third electrode layer comprising Au.

19.

(New)

- 20. (New) The electrode structure according to claim 19, wherein said first electrode layer has a thickness in a range from 1 to 500 nm.
- 21. (New) The electrode structure according to claim 19, wherein said second electrode layer has a thickness of 5 nm or more.
- 22. (New) The electrode structure according to claim 19, wherein said first electrode layer comprises a nitride of a metal included in said first metal group, and also comprises a compound of Ga and Ni. a metal included in said second metal group.
- 23. (New) An electrode structure on a p-type III group nitride semiconductor layer, comprising first, second and third electrode layers successively stacked on said semiconductor layer,

said first electrode layer comprising at least one selected from a first-metal group consisting of Hf, and said second electrode layer comprising at least one selected from a second metal group consisting of Ni, Pd and Co, and

said third electrode layer comprising including Au.

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- 24. (New) The electrode structure according to claim 23, wherein said first electrode layer has a thickness in a range from 1 to 500 nm.
- 25. (New) The electrode structure according to claim 23, wherein said second electrode layer has a thickness of 5 nm or more.
- 26. (New) The electrode structure according to claim 23, wherein said first electrode layer comprises a nitride of a metal included in said first metal group, and also comprises includes a compound of Ga and a metal included in said second metal group.
- 27. (New) An electrode structure on a p-type III group nitride semiconductor layer, comprising first, second and third electrode layers successively staked on said semiconductor layer;

said first electrode layer comprising a mixture containing a nitride of at least one selected from a first metal group consisting of Hf, Zr, Nb, Ta and Sc, and a Ga compound comprising of at least one selected from a second metal group consisting of Ni or and Co,

said second electrode layer comprising Ni, and said third electrode layer comprising Au.

- 28. (New) The electrode structure according to claim 27, wherein said second electrode layer has a thickness of 5 nm or more.
- 29. (New) The electrode structure according to claim 27, wherein said third electrode layer has a thickness of 5 nm or more.